

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/708,608	IADANZA ET AL.	
	<b>Examiner</b> Sun J. Lin	<b>Art Unit</b> 2825	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	4	4/27/2006	JSL
716	5	4/27/2006	JSL
716	1,2	4/27/2006	JSL